

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination LITKE ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,198,979 B1	03-2001	Konno	700/98
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Eck et al., Multiresolution Analysis of Arbitrary Meshes, 1995, ACM, pp.173-174
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.